

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of Applicants:

Beaman et al.

Serial No.: 09/382,834

Filed: August 25, 1999

For: HIGH DENSITY INTEGRATED CIRCUIT APPARATUS, TEST PROBE AND  
METHODS OF USE THEREOF

Date: October 29, 2008

Group Art Unit: 2829

Examiner: V. P. Nguyen

Docket No.: YOR919930028US5

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**RESPONSE AFTER FINAL ACTION DATED 05/04/2008 AND**  
**ADVISORY ACTION DATED 10/14/2008**

Sir:

In response to the Final Office Action dated 05/04/2008 and Advisory Action dated 10/14/2008, please consider the following.